

EE 6250 VLSI Testing Homework#3

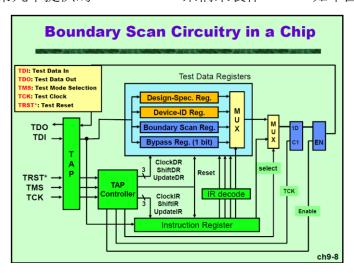
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VLSI Testing Homework #3

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Source Code (Environment: NC-verilog)

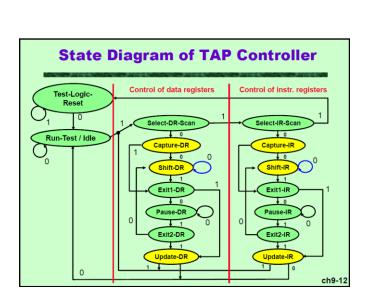
主要架構參考自課本第九章提供的 IEEE 1149.1 架構來製作 BSC,如下圖所示:



各細部 module 將在底下詳述其功能

(1) TAP-Controller

根據講義提供之狀態圖為其設定 FSM,訊號皆由 TMS 來進行控制。



```
always @ (posedge tck)
                   Run_Test_Idle: if(tms == 0)
else
                                                                       state = Run Test Idle;
                                                                       state = Select_Dr;
state = Capture Dr;
                   Select Dr: if(tms == 0)
                         else
                                                                       state = Select_Ir;
state = Shift_Dr;
state = Exit1_Dr;
                   Capture_Dr: if(tms == 0)
                   Shift_Dr:
else
Exit1_Dr:
                                                                       state = Shift_Dr;
state = Exit1_Dr;
state = Pause_Dr;
                                      if(tms == 0)
                                      if(tms == 0)
                                                                       state = Update_Dr;
state = Pause_Dr;
state = Exit2_Dr;
                          else
                   Pause_Dr:
                   Exit2 Dr: if(tms == 0)
                                                                        state = Shift Dr;
                                                                       state = Shirt_Br;
state = Update_Dr;
state = Run_Test_Idle;
state = Select_Dr;
                   Update_Dr: if(tms == 0)
else
                   Select_Ir: if(tms == 0)
                                                                       state = Capture_Ir;
state = Reset;
                   state = Shift_Ir;
state = Exit1_Ir;
state = Shift_Ir;
                                                                       state = Exit1_Ir;
state = Pause_Ir;
state = Update_Ir;
                   Pause_Ir:
else
                                                                       state = Pause_Ir;
state = Exit2_Ir;
state = Shift_Ir;
                                     if(tms == 0)
                   Exit2_Ir: if(tms == 0)
else
                                                                        state = Update Ir;
                                                                       state = Opdate_II,
state = Run_Test_Idle;
state = Select_Dr;
state = Run_Test_Idle;
                   Update_Ir: if(tms == 0)
                   else
Reset: if(tms == 0)
                                                                       state = Reset;
state = Reset;
                   else
default:
```

```
// Output Assignments
       States of TAP Controller
                                               assign reset = (state == 4'b1000);
                                               assign select = state[3]; // 1 for IR, 0 otherwise
- Test-Logic-Reset: normal mode
- Run-Test/Idle: wait for internal test such as BIST
                                               assign capture ir = (state == Capture Ir);
- Select-DR-Scan: initiate a data-scan sequence
                                               assign shift_ir = (state == Shift_Ir);
- Capture-DR: load test data in parallel
                                               assign update_ir = (state == Update_Ir);
- Shift-DR: load test data in series
                                               assign clock_ir = ((capture_ir || shift_ir || update_ir) && ~tck);
- Exit1-DR: Finish phase-1 shifting of data
- Pause-DR: Temporarily hold the scan operation
                                               assign capture_dr = (state == Capture_Dr);
          (allow the bus master to reload data)
                                               assign shift dr = (state == Shift Dr);
- Exit2-DR: finish phase-2 shifting of data
                                               assign update dr = (state == Update Dr);
                                               assign clock_dr = ((capture_dr || shift_dr || update_dr) && ~tck);

    Update-DR: parallel load from associated shift registers

                                          ch9-13 assign enable = shift_ir || shift_dr;
```

根據目前的 state 輸出其訊號為 1,否則便為 0。

(2) Bypass-Register

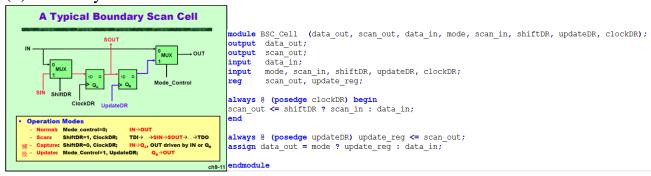
```
module Bypass_Register(scan_out, scan_in, shiftDR, clockDR);
  output    scan_out;
  input    scan_in, shiftDR, clockDR;
  reg     scan_out;

always @ (posedge clockDR) scan_out <= scan_in & shiftDR;</pre>
```

endmodule

Bypass-Register 則為收到 shiftDR 的訊號後去傳遞 scan_in 的值到 scan_out, 若沒收到則不傳遞 scan_in 的值到 scan_out (即 hold 住原本 scan_out 的值)。

(3) Boundary Scan Cell



BSC 部分亦是根據講義架構完成,如上圖所示,主要概念就是用 shiftDR 及 mode_control 去做兩個 multiplier 的控制,以及分別由 ClockDR 及 UpdateDR 控制兩個 DFF 的訊號進出。

(4) Instruction Decoder

收到 ClockIR、ShiftIR、UpdateIR 訊號後根據收到的訊號進行判斷,傳遞所要傳遞的訊號給BSC。

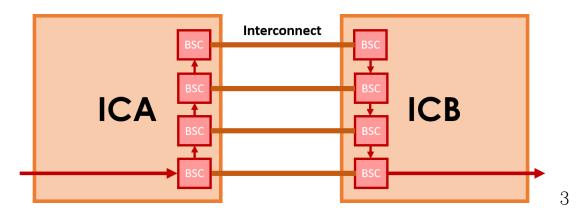
(5) Instruction Register

```
module Instruction_Register (data_out, data_in, scan_out, scan_in, shiftIR, clockIR, updateIR, reset_bar);
parameter IR size = 2;
output [IR_size -1: 0] data_out;
output
                scan_out;
       [IR_size -1: 0] data_in;
input
input
                scan_in;
                shiftIR, clockIR, updateIR, reset bar;
reg [IR_size -1: 0] IR_Scan_Register, IR_Output_Register;
assign
                data out = IR Output Register;
                scan out = IR Scan Register [0];
always @ (posedge clockIR) IR_Scan_Register <= shiftIR ? {scan_in, IR_Scan_Register [IR_size - 1: 1]} : data_in;</pre>
always @ ( posedge updateIR or negedge reset_bar)
  if (reset_bar == 0) IR_Output_Register <= ~(0);</pre>
                                                          // Fills IR with 1s for BYPASS instruction
  else IR_Output_Register <= IR_Scan_Register;</pre>
```

endmodule

儲存收到的訊號指令,並且根據 ShiftIR 訊號判斷是否要將新收到的指令傳遞出去。

但因為之後發現在實作的一些困難,因此我簡化省略了 IR-Cell 的部分,直接從 Host 端控制 shiftDR,mode 等訊號,而且原題目指要求傳遞 4 條 IC 間的 interconncet,因此最後設計僅使用 Boundary Scan Cell 來進行 Boundary Scan Test,而因為有四條 interconnect,因此需要八組 BSC,如下圖所示:



下圖為實際的程式碼, interconnect 的部分使用 4bit 的 data, 每個 bit 代表一條 interconnect, 並且我可以直接從 out 端看到我輸出的結果方便我進行 pattern 是否完整傳輸的驗證。

```
module IC (TDO, data out, TDI, data in, Mode Control, ShiftDR, UpdateDR, ClockDR, RST);
    output [3:0] data out;
    output TDO;
    input [3:0] data in;
    input TDI, Mode_Control, ShiftDR, UpdateDR, ClockDR, RST;
    wire scan1, scan2, scan3, scan4, q1;
    BSC Cell B1(.data out(data out[0]), .scan out(scan1), .data in(data in[0]), .scan in(TDI),
                .mode (Mode_Control) , .shiftDR (ShiftDR) ;
                .updateDR(UpdateDR), .clockDR(ClockDR));
    BSC Cell B2(.data out(data out[1]), .scan out(scan2), .data in(data in[1]), .scan in(scan1),
                .mode (Mode_Control), .shiftDR (ShiftDR),
                .updateDR(UpdateDR), .clockDR(ClockDR));
    BSC_Cell B3(.data_out(data_out[2]), .scan_out(scan3), .data_in(data_in[2]), .scan_in(scan2),
                .mode (Mode_Control), .shiftDR (ShiftDR),
                .updateDR(UpdateDR), .clockDR(ClockDR));
    BSC Cell B4(.data out(data out[3]), .scan out(scan4), .data in(data in[3]), .scan in(scan3),
                .mode(Mode_Control), .shiftDR(ShiftDR),
                .updateDR(UpdateDR), .clockDR(ClockDR));
endmodule
```

每個 IC 有 4 個 Boundary Scan Cell, 並且 in/out 端連接 bit-by-bit 的連接 data in/data out, 並且用四條 wire(scan1~scan4)串聯形成 scan chain, Boundary Scan Cell 部分上面設計以闡述過故不在贅述。

Simulation Result (Environment: nWave)

由 ICA 輸入 TDI, 之後使用 shiftDR 移動 TDI 輸入的 pattern 進行 scan chain 的移動, 之後由 ICB data in 端接收到的資訊,之後再 scan out 出 pattern 完成一次的 pattern communication。 之後就由 TDI_a 進行灌入 pattern 的動作, 設定 clock period 為 10ns, 因此灌入一次完整的 pattern 需要 40ns, 如下圖為每組的 pattern 詳細參數:

```
//input pattern 0100
                                                                           //input pattern 1100
//iuput pattern 0000
                                                 //input pattern 1000
                                                                           #10 tdi_a = 1;
#10 tdi_a = 0;
                        #10 tdi_a = 0;
                                                  #10 tdi a = 1;
                                                                           #10 tdi a =
#10 tdi_a = 0;
                        #10 tdi_a = 1;
                                                  #10 tdi_a = 0;
                        #10 tdi a = 0;
#10 tdi a = 0;
                                                  #10 tdi a = 0;
                                                                           #10 tdi a = 0
  0 tdi a = 0;
                                                 #10 tdi_a = 0;
                                                                           //input pattern 1101
//input pattern 0001 //input pattern 0101
                       #10 tdi a = 0:
#10 tdi a = 0;
                                                 #10 tdi a = 1;
                                                                           #10 t.di a =
                        #10 tdi_a = 0;
                       #10 tdi_a = 1;
#10 tdi a = 1;
                                                 #10 tdi a = 1:
                                                                          //input pattern 1110
#10 tdi_a = 1;
//input pattern 0010 //input pattern 0110
                                               //input pattern 1010
                       #10 tdi_a = 0;
#10 tdi_a = 1;
#10 tdi_a = 1;
                                                 #10 tdi_a = 1;
#10 tdi a = 0;
                                                                           #10 tdi_a = 1;
#10 tdi a = 0;
                                                                           #10 tdi_a = 0;
                       #10 tdi_a = 0;
                                                  #10 tdi a = 0;
                                                                           //input pattern 1111
                                                  //input pattern 1011
//input pattern 0011 //input pattern 0111
                                                                          #10 tdi_a = 1;
#10 tdi a = 1;
                                                 #10 tdi_a = 1;
#10 tdi_a = 0;
                        #10 tdi_a = 0;
 10 tdi_a = 0;
                        #10 tdi_a = 1;
                                                  #10 tdi_a = 0;
                                                  #10 tdi a = 1;
                                                                           #10 tdi a = 1;
#10 tdi_a = 1;
                        #10 tdi a = 1;
                                                 #10 tdi_a = 1;
```

因此需要每 40ns 才可以在 out 端看到完整的結果,在使用 nWave 的時候需要多以下指令來產生 nWave 觀看波型圖時所使用的.sfdb 檔,如下所示:

```
initial begin
$fsdbDumpfile("TOP.fsdb");
$fsdbDumpvars;
end
```

模擬後結果如下圖所示:



因為 pattern 從 ICA 的第一個 BSC 到 ICB 的第四個 BSC 須要經過 8 個完整的 positive edge 的時間,外加 dfilp-flop 本身需要一個 clock cylce 的時間,因此黃色虛線的位置為第一個從 ICB 的 data out 完整吃到 pattern 產生的結果。

1/iclab79/testing/TOP.fsdb@ic21.cs.nthu.edu.tw



之後每個四個 clock cycle 便可以看到完整 pattern output 的結果,如上圖所示依序為 1,2,3...



之後結果依序如上圖所示,值到完整個 16 組 pattern 產生出來後,模擬便會結束。

此外為了方便助教操作,我有附上 Makefile 可以直接使用 make sim 來進行模擬,產生的 nWave 觀看波型用的 fsdb 檔也一併附上。